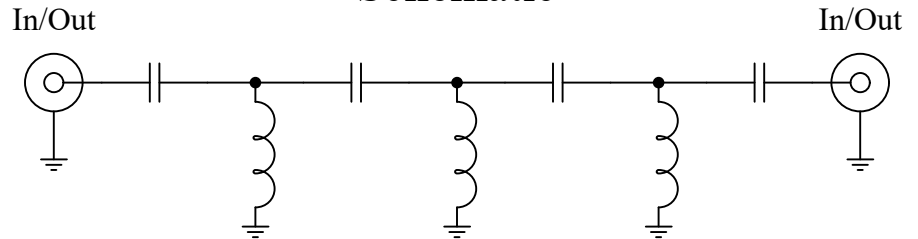


High Pass Filter
50Ω SMA
1000 MHz 7th Order
Part Number: CHPFL-1000



Schematic



Features:

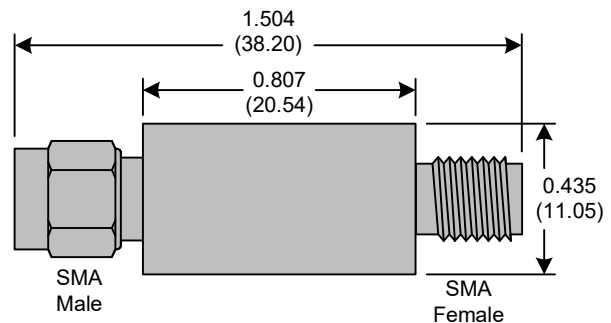
- 7th Order Butterworth Response
- 50Ω SMA Connectors

Applications:

- Test Equipment
- Lab Use

Maximum Ratings:

- +36dBm (4 Watts)
- Operating Temperature: -40°C to 85°C
- Storage Temperature: -55°C to 100°C



Crystek's line of High Pass Filters are designed in a rugged SMA housing. This filter line has excellent out-of-band rejection. Designed for Test Equipment and General Lab Use.

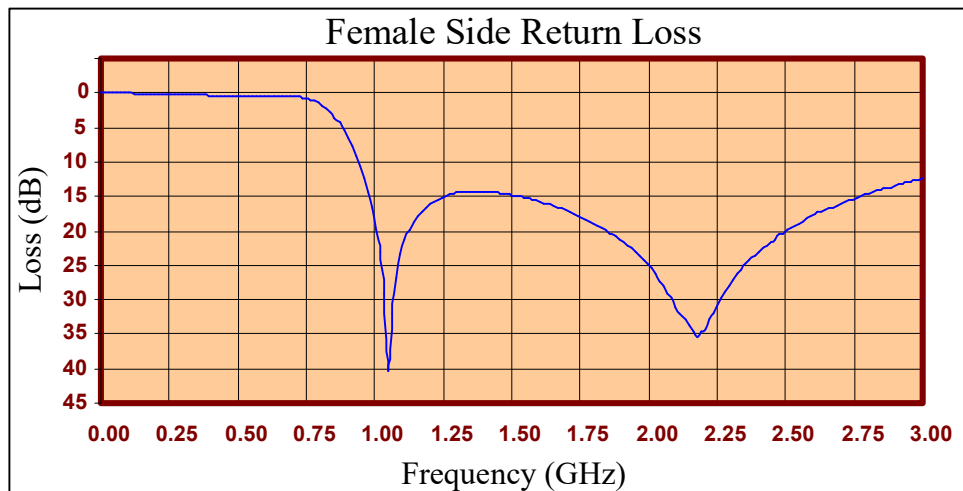
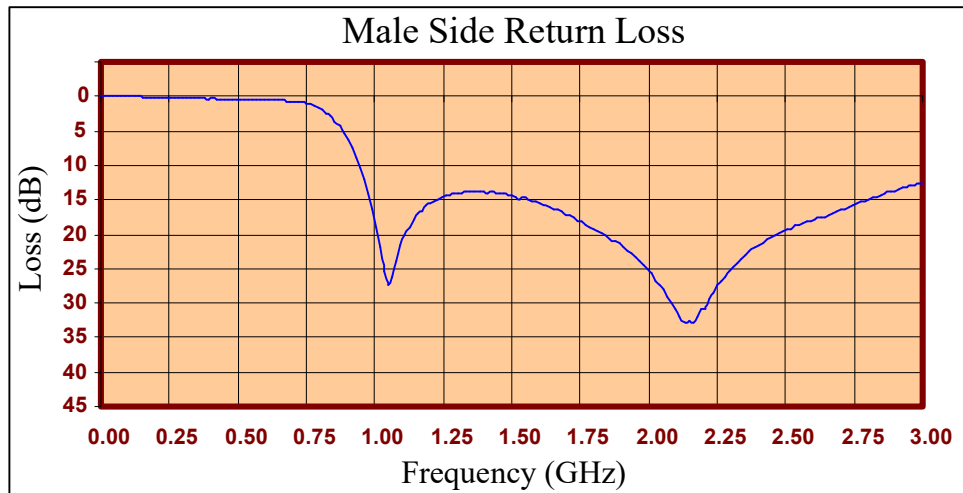
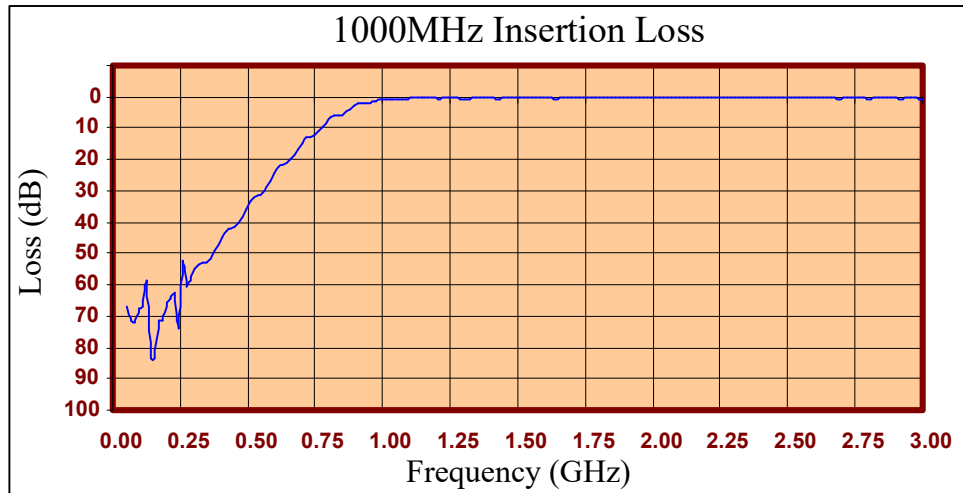
Product Control:

Crystek Part Number:	CHPFL-1000	Release Date:	16-Apr-2026
Revision Level:	F	Responsible:	K. Piotrowicz

High Pass Filter

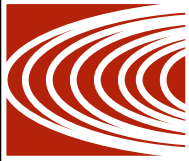
50Ω SMA

1000 MHz 7th Order



Product Control:

Crystek Part Number:	CHPFL-1000	Release Date:	16-Apr-2026
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High Pass Filter
 50Ω SMA
 1000 MHz 7th Order

FREQ (MHz)	INSERTION LOSS (dB)	Male Return Loss (dB)	Female Return Loss (dB)
0.3	100.84	0.00	0.00
15.3	106.89	0.00	0.00
30.3	98.75	0.01	0.00
45.3	93.17	0.01	0.00
60.3	102.59	0.02	0.03
75.3	106.75	0.02	0.04
90.3	86.87	0.01	0.02
105	84.46	0.02	0.04
120	77.84	0.04	0.07
135	76.57	0.05	0.06
150	76.06	0.06	0.13
165	74.02	0.12	0.13
180	72.55	0.12	0.19
195	69.63	0.11	0.17
210	67.13	0.09	0.14
225	63.09	0.10	0.16
240	59.82	0.13	0.20
255	59.53	0.13	0.20
270	60.03	0.09	0.23
285	59.87	0.13	0.21
300	58.84	0.23	0.23
330	53.95	0.21	0.24
405	47.57	0.32	0.36
450	40.87	0.38	0.39
510	35.71	0.47	0.45
585	24.12	0.54	0.47
705	12.88	0.70	0.49
810	5.39	1.97	1.83
900	3.20	6.30	6.48
1005	0.91	18.97	19.86
1245	0.47	14.61	15.11
1500	0.49	14.38	14.85
1755	0.36	18.18	18.10
1995	0.23	25.08	24.88
2250	0.62	27.49	30.78
2505	0.49	19.39	19.90
2745	0.49	15.81	15.38
3000	0.55	12.58	12.36

Product Control:

Crystek Part Number:	CHPFL-1000	Release Date:	16-Apr-2026
Revision Level:	F	Responsible:	K. Piotrowicz

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